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determining two-dimensional structure information from the image at the first visual

frequency; and

determining height information for the structure from the path of the [laser] coherent light beam at the second visual frequency.

16. (Amended) The method of inspecting at least one structure on a surface of an object of claim 9 further comprising illuminating the surface of the object with a second [laser] coherent light source mounted on a side of the object which is displaced 90 degrees from the first [laser] coherent light source, said second [laser] coherent light source illuminating the surface in a path that is perpendicular to the path illuminated by the first [laser] coherent light source.

REMARKS

Entry of the foregoing preliminary amendment is respectfully requested. This preliminary amendment clearly adds no new matter to the application, and is not being submitted in response to any substantive Examiner's action.

Respectfully submitted,

Date: January 7, 2000

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